Notice of References Cited Application/Control No. 10/023,564 Examiner David Q. Nguyen Applicant(s)/Patent Under Reexamination HOISKO ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

	Document Number Date						
*		Country Code-Number-Kind Code	MM-YYYY	Name	Classification		
	Α	US-					
	В	US-					
	С	US-					
	D	US-					
	E	US-					
	F	US-					
	G	US-					
	н	US-					
	_	US-					
	J	US-					
	к	US-					
	L	US-		·			
	М	US-		·			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N	JP410257131A	09-1998	Japan	Nozaki, Masataka		
	0						
	Р						
	Q						
	R	,					
	s						
	Т						

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.